## Notice of References Cited Application/Control No. 10/526,595 Applicant(s)/Patent Under Reexamination VORBACH, MARTIN Examiner Don P. Le Application/Control No. Applicant(s)/Patent Under Reexamination VORBACH, MARTIN Page 1 of 1

## U.S. PATENT DOCUMENTS

÷		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0103839	08-2002	Ozawa, Kunihiko	708/490
*	В	US-5,821,774	10-1998	Veytsman et al.	326/39
*	O	US-6,633,181	10-2003	Rupp, Charle' R.	326/40
*	D	US-6,188,240	02-2001	Nakaya, Shogo	326/39
*	Е	US-6,476,634	11-2002	Bilski, Goran	326/40
*	F	US-6,803,787	10-2004	Wicker, Jr., David J.	326/46
*	G	US-2003/0001615	01-2003	Sueyoshi et al.	326/41
*	Ξ	US-4,882,687	11-1989	Gordon, Dorothy A.	345/522
*	-	US-RE34,444	11-1993	Kaplinsky, Cecil H.	326/39
*	7	US-6,026,481	02-2000	New et al.	712/43
	K	US-			
	L	US-			
	M	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S.					
	Т				•	

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	υ						
	٧						
	w						
	х						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.